


<b>Search Notes</b> 	<b>Application/Control No.</b> 10544126	<b>Applicant(s)/Patent Under Reexamination</b> ARITSUKA, TOMOHIKO
	<b>Examiner</b> Kaplan, Hal I	<b>Art Unit</b> 2836

SEARCHED			
Class	Subclass	Date	Examiner
307	17	3/28/2007	HK
307	82	3/28/2007	HK
307	83	3/28/2007	HK
361	35	3/28/2007	HK
361	36	3/28/2007	HK
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323	271	3/28/2007	HK
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323	276	3/28/2007	HK
363	25	3/28/2007	HK
363	39	3/28/2007	HK

SEARCH NOTES		
Search Notes	Date	Examiner
361/67 (consulted Stephen W. Jackson)	3/29/2007	HK
323/222,271-276; 363/25,37,39,41 (consulted Rajnikant Patel)	3/28/2007	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	3/28/2007	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	3/29/2007	HK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner